

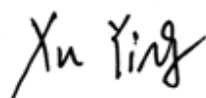
OTA TEST REPORT

Applicant Logitech (China) Technology Co., Ltd.
Product Regera
Model 99PC-REGERA-SK04
Report No. Y2303A0294-T1V3
Issue Date May 29, 2023

TA Technology (Shanghai) Co., Ltd. tested the above equipment in accordance with the requirements in **ANSI/IEEE Std 149-2021**. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.



Test Engineer: Zhang Tao



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Version	Revision description	Issue Date
Rev.0	Initial issue of report.	April 11, 2023
Rev.1	Update model information.	April 19, 2023
Rev.2	Add layout coordinate information in page 17.	April 21, 2023
Rev.3	Update description.	May 29, 2023
Note: This revised report (Report No.: Y2303A0294-T1V3) supersedes and replaces the previously issued report (Report No.: Y2303A0294-T1V2). Please discard or destroy the previously issued report and dispose of it accordingly.		

1. Test Laboratory

1.1. Notes of the Test Report

This report shall not be reproduced in full or partial, without the written approval of **TA Technology (Shanghai) Co., Ltd.** The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. Measurement Uncertainties were not taken into account and are published for informational purposes only. This report is written to support regulatory compliance of the applicable standards stated above.

1.2. Test Facility

A2LA (Certificate Number: 3857.01)

TA Technology (Shanghai) Co., Ltd. has been listed by American Association for Laboratory Accreditation to perform measurement.

1.3. Testing Location

Company: TA Technology (Shanghai) Co., Ltd.
Address: Building 3, No.145, Jintang Rd, Pudong Shanghai, P.R.China
City: Shanghai
Post code: 201201
Country: P. R. China
Contact: Xu Kai
Telephone: +86-021-50791141/2/3
Fax: +86-021-50791141/2/3-8000
Website: <http://www.ta-shanghai.com>
E-mail: xukai@ta-shanghai.com

1.4. Laboratory Environment

Temperature	Min. =19°C, Max. = 25°C	
Relative humidity	Min. =40%, Max. =72%	
Shield effect	0.7-6GHz	> 100dB
Ground resistance	<0.5Ω	

2. General Description of Equipment Under Test

2.1. Applicant and Manufacturer Information

Applicant Name	Logitech (China)Technology Co.,Ltd.
Applicant address	20F, Yueda 889, No.1111, Changshou Road, Jing'an District Shanghai, China
Manufacturer Name	Logitech (China)Technology Co.,Ltd.
Manufacturer address	20F, Yueda 889, No.1111, Changshou Road, Jing'an District Shanghai, China

2.2. General Information

EUT Description	
Product Name:	Regera
Model	99PC-REGERA-SK04
HW Version:	V0.4
SW Version:	V1.2.34
Antenna Type:	PCB Antenna
Antenna Manufacturer:	Suike Electronics Co.,Ltd.
Test Frequency:	2400MHz ~ 2483.5MHz
Note: The EUT is sent from the applicant to TA and the information of the EUT is declared by the applicant. All indications of Pass/Fail in this report are opinions expressed by TA Technology (Shanghai) Co., Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only.	

2.3. Test Date

The test is performed on March 29, 2023

2.4. Received Date

The sample was received on March 17, 2023

2.5. Applied Standards

According to the specifications of the manufacturer, it must comply with the requirements of the following standards:

Test Method: **ANSI/IEEE Std 149-2021**

3. Test Conditions

3.1. Test Configuration

Great-Circle-Cut method is used to measure the antenna 3D GAIN of EUT in OTA qualified anechoic chamber. Equipment Under Test (EUT) geometry centre vertical projection at the centre of platform, the distance from EUT to measurement antenna is 5m.

3.2. Test Measurement

Spherical coordinate system

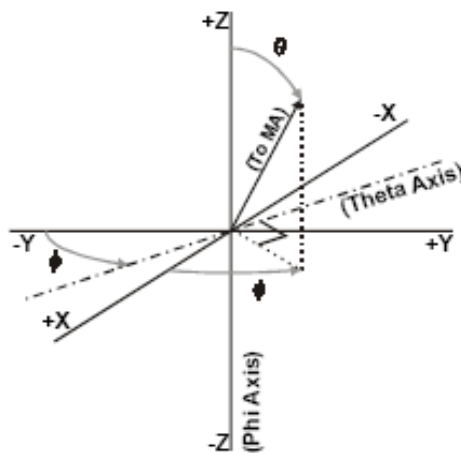
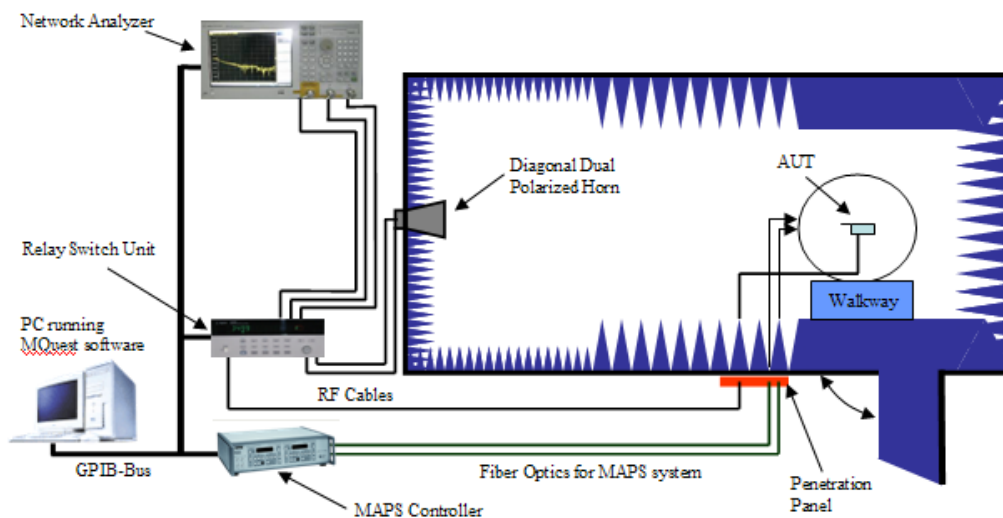


Figure 1 Test coordinate system

Note: Theta is from 0~180 degree. Phi is from 0~360. Rotate the EUT and record the Data, the step of rotation is 15 degree.

Test Setup



4. Test Results

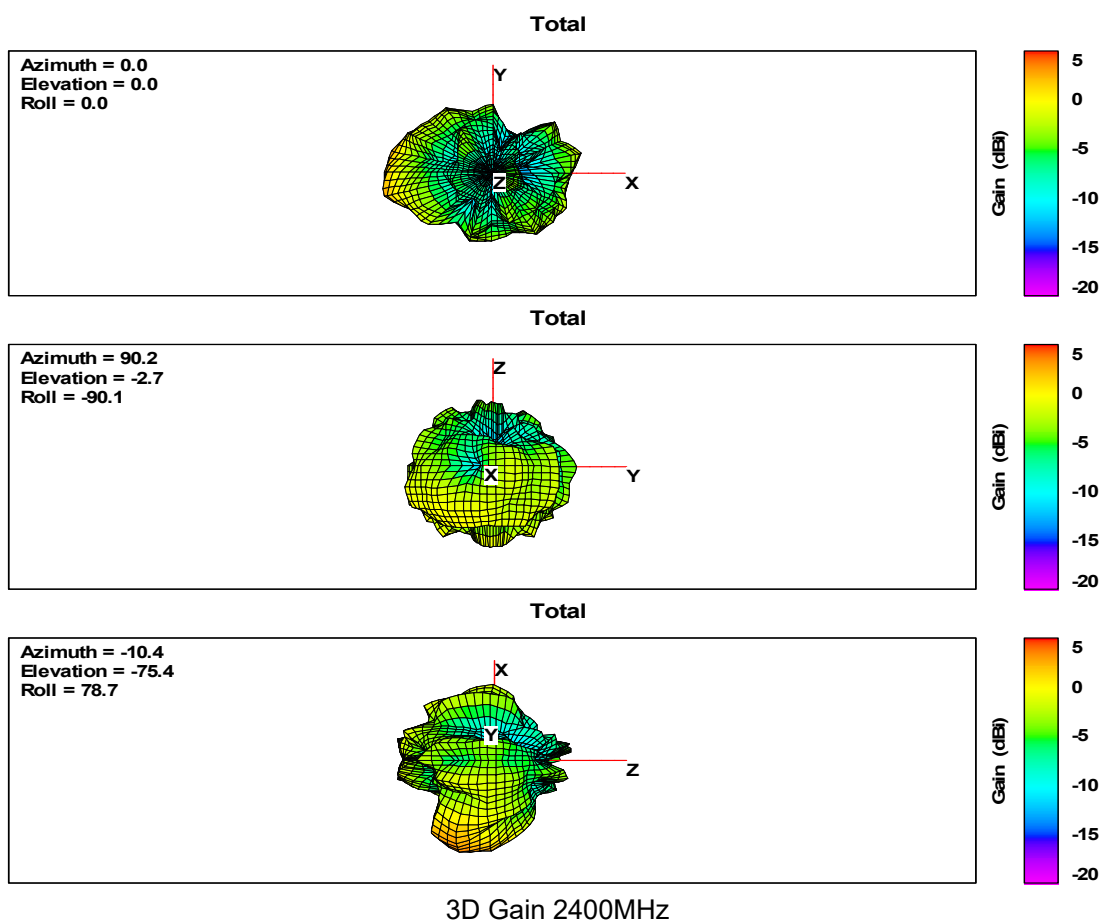
4.1. Gain and Efficiency

Test Location	Test State	Frequency (MHz)	Efficiency (%)	Gain (dBi)	Note
3D Gain	Free Space	2400	48.05	3.67	/
		2402	48.20	3.69	
		2404	48.43	3.63	
		2440	52.09	4.98	
		2441	52.37	5.13	
		2478	60.07	5.38	
		2480	60.99	5.52	

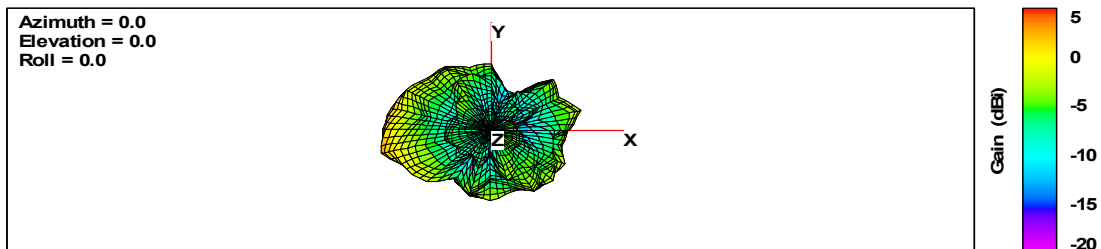
5. Equipment List

Type of Equipment	Manufacture	Model Number	S/N	Calibration Date	Expiration Time
Anechoic Chamber	ETS	AMS-8500	CT-001157-1219	2020-05-17	2025-05-16
EMCenter_Switch Control System	ETS	7006/7001	00059957/MY42001152	/	/
Diagonal Dual Polarized Horn	ETS	ETS 3164-04	00062743	2020-04-14	2025-04-13
Network Analyzer	Keysight	E5071B	MY42404014	2022-05-14	2023-05-13
Software	ETS	EMQuest™	1.16	/	/

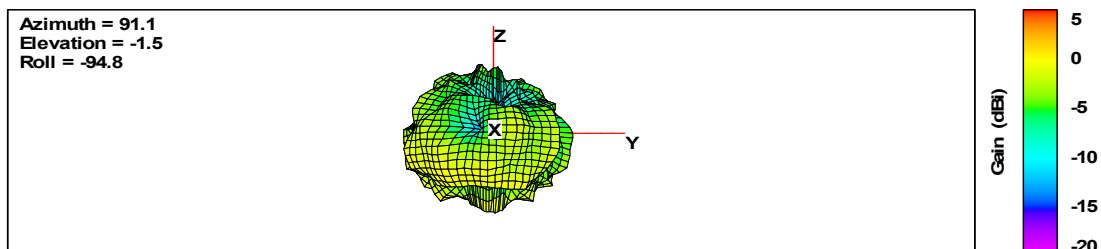
ANNEX A: 3-D Pattern Plots



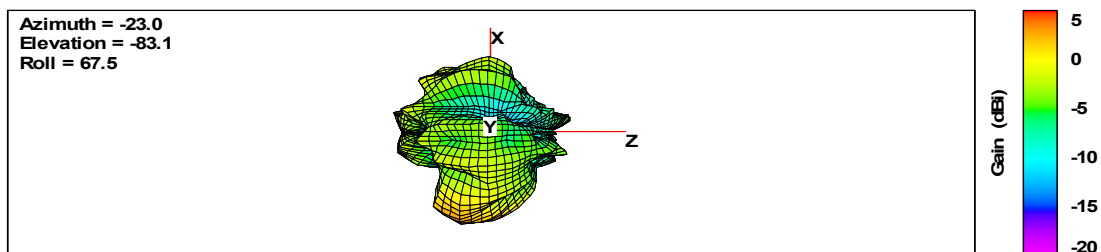
Total



Total

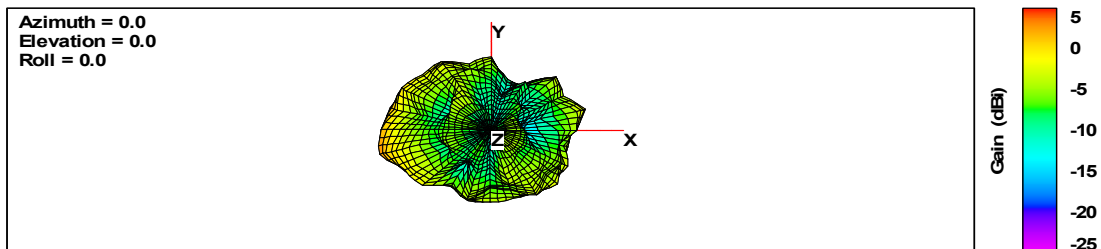


Total

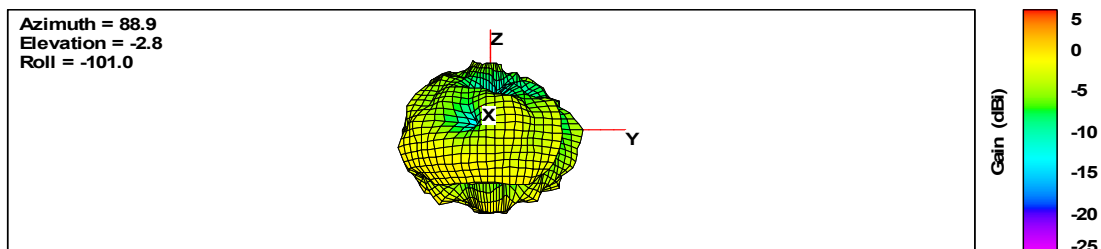


3D Gain 2402MHz

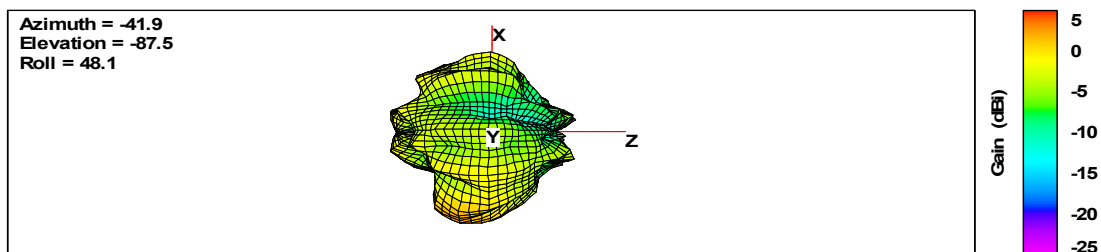
Total



Total

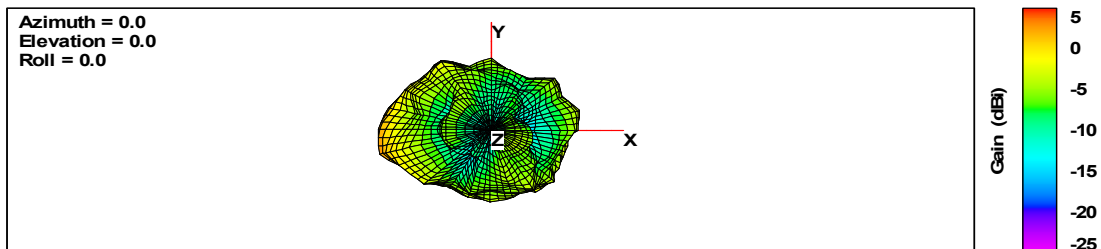


Total

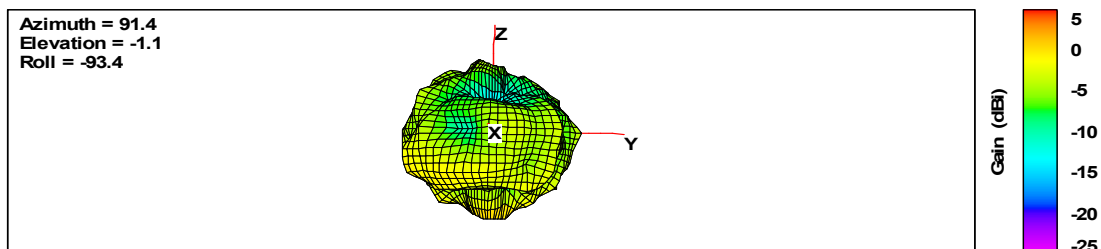


3D Gain 2404MHz

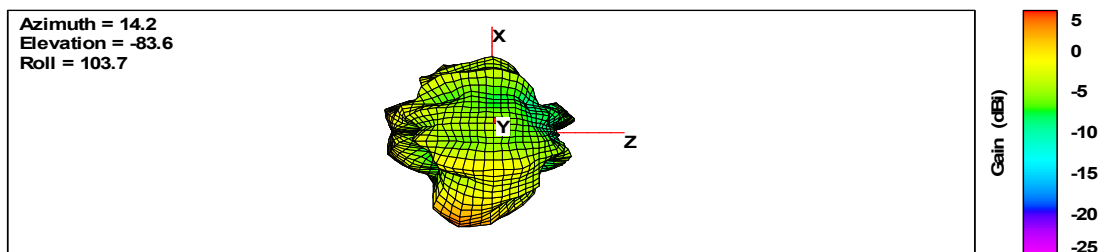
Total



Total

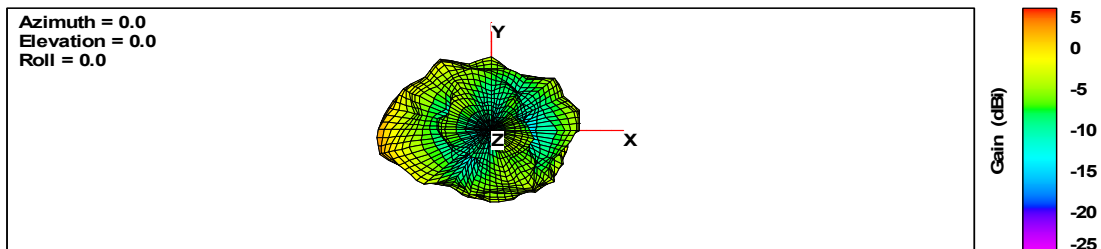


Total

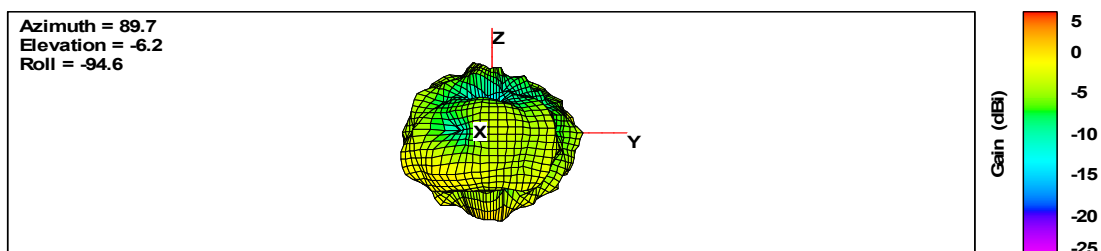


3D Gain 2440MHz

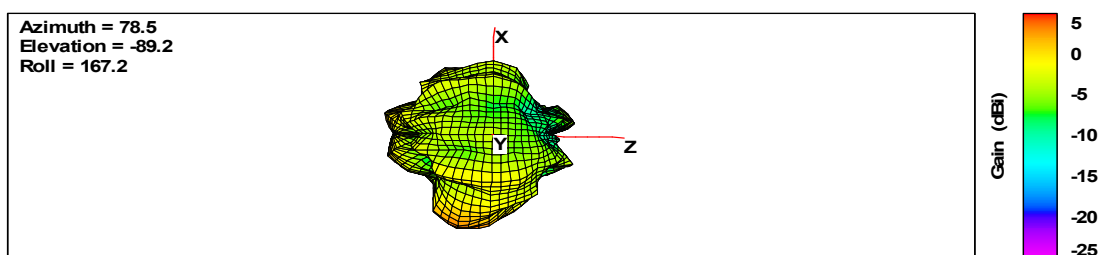
Total



Total

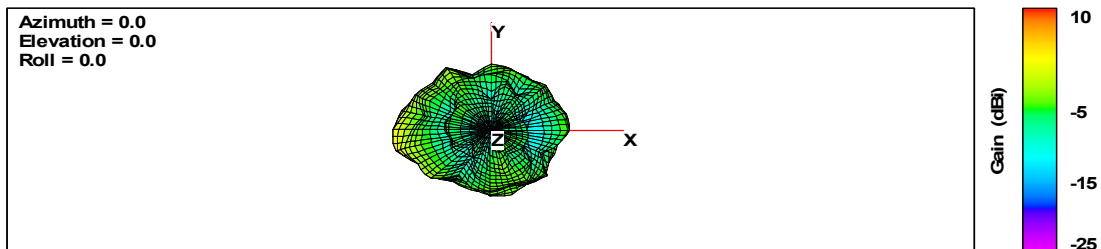


Total

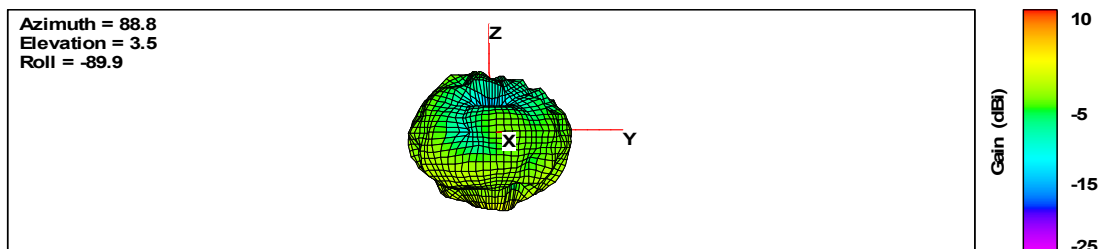


3D Gain 2441MHz

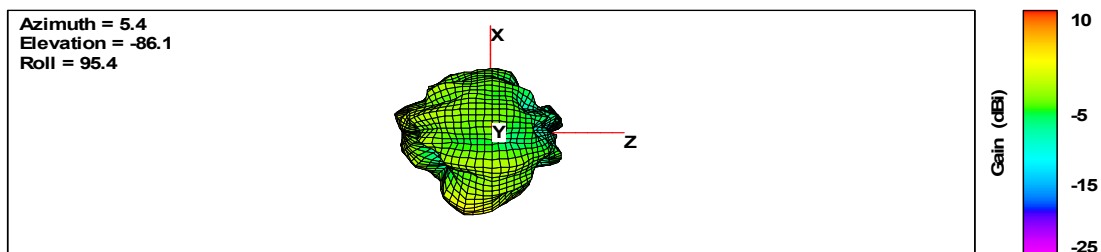
Total



Total

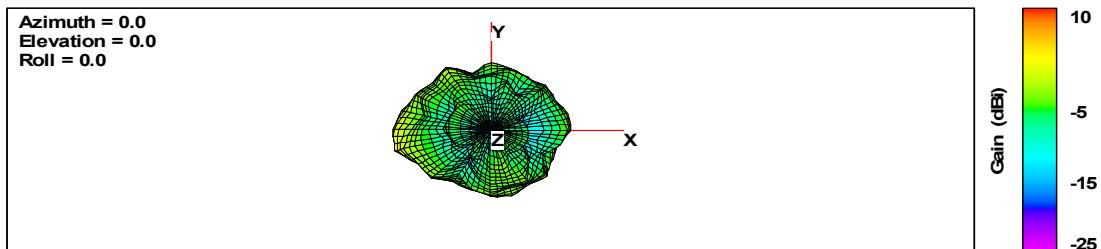


Total

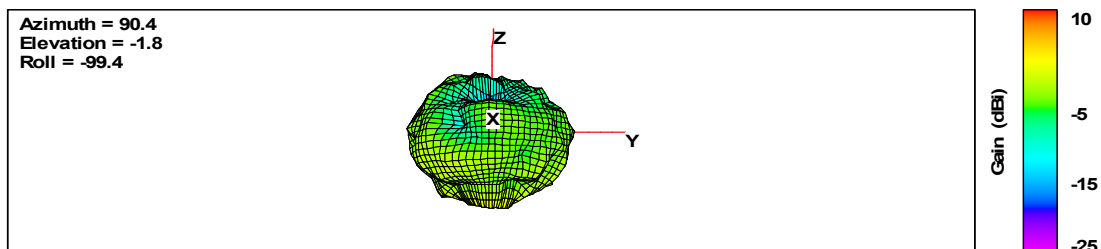


3D Gain 2478MHz

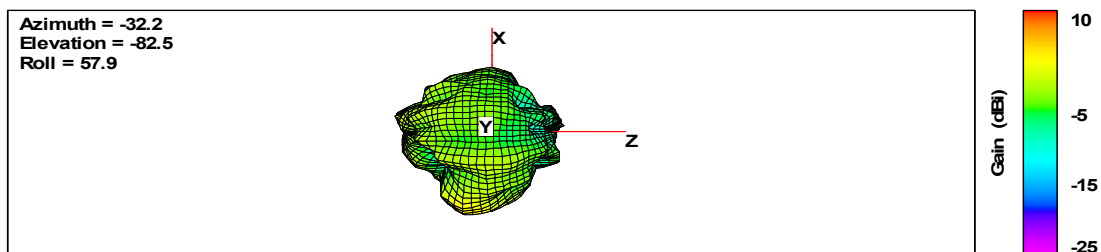
Total



Total



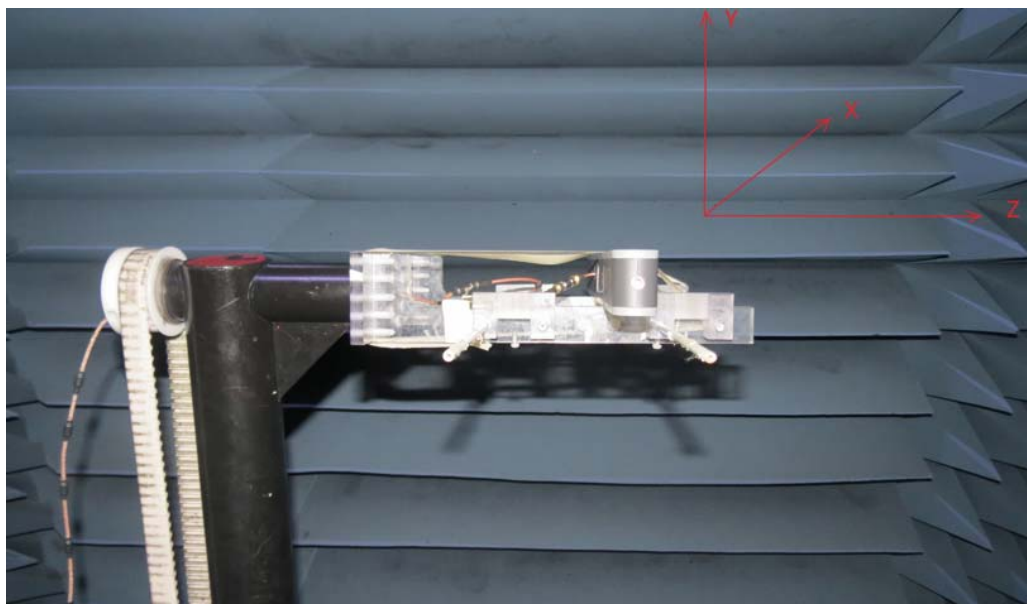
Total



3D Gain 2480MHz

ANNEX B: THE EUT APPEARANCE AND TEST CONFIGURATION

Test Configuration



Picture 1 Test Setup